

# Fast switching diode chip in EMCON 3-Technology

## **FEATURES:**

- 600V EMCON 3 technology 70 μm chip
- soft, fast switching
- low reverse recovery charge
- small temperature coefficient

## This chip is used for:

- power module
- discrete components



## **Applications:**

drives

Chip Type	$V_R$	I <sub>F</sub>	Die Size	Package
SIDC08D60C6	600V	30A	3.46 x 2.3 mm <sup>2</sup>	sawn on foil

#### **MECHANICAL PARAMETER:**

Raster size	3.46 x 2.3			
Area total / active	7.96 / 5.77	mm <sup>2</sup>		
Anode pad size	2.76 x 1.6			
Thickness	70	μm		
Wafer size	150	mm		
Flat position	180	deg		
Max. possible chips per wafer	1818 pcs			
Ssivation frontside Photoimide				
Anode metallization	3200 nm AlSiCu			
Cathode metallization	bonding			
Die bond	electrically conductive glue or solder			
Wire bond	AI, ≤500μm			
Reject ink dot size	Ø 0.65mm; max 1.2mm			
Recommended storage environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C			



## **Maximum Ratings**

Parameter	Symbol	Condition	Value	Unit
Repetitive peak reverse voltage	$V_{RRM}$		600	V
Continuous forward current limited by	1-		1)	
$T_{jmax}$	I <sub>F</sub>			Α
Maximum repetitive forward current	1		60	
limited by T <sub>jmax</sub>	<b>/</b> FRM		00	
Operating junction and storage temperature	$T_{\rm j}$ , $T_{ m stg}$		-40+175	°C

<sup>1)</sup> depending on thermal properties of assembly

# Static Electrical Characteristics (tested on chip), $T_{\rm j}$ =25 °C, unless otherwise specified

Parameter	Symbol	Condi	Value			Unit	
raiailletei	Syllibol	Condi	itions	min.	Тур.	max.	Joint
Reverse leakage current	I <sub>R</sub>	V <sub>R</sub> = 600 V	T <sub>j</sub> = 25° C			27	μΑ
Cathode-Anode breakdown Voltage	V <sub>Br</sub>	I <sub>R</sub> = 0.25mA	$T_j=25^{\circ}C$	600			V
Forward voltage drop	$V_{F}$	I <sub>F</sub> = 30 A	<i>T<sub>j</sub>=25°C</i>	1.25	1.6	1.95	٧

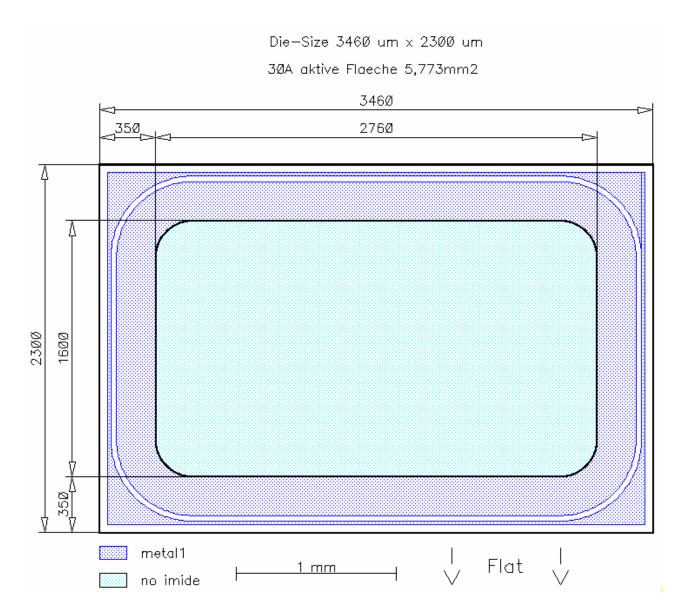
# Dynamic Electrical Characteristics (verified by design/characterization), inductive load

Parameter	Symbol	Conditions		Value 2)			Unit
raiailletei	Syllibol			min.	Тур.	max.	7 01111
Peak reverse recovery current	I <sub>RM</sub>	$I_F=30A$ $di/dt=2100A/\mu s$ $V_R=300V$ $V_{GE}=-15V$	$T_j = 25 \text{ °C}$ $T_j = 125 \text{ °C}$ $T_j = 150 \text{ °C}$		44.0 49.0 50.0		А
Recovered charge	Q <sub>r</sub>	$I_F=30A$ $di/dt=2100A/\mu s$ $V_R=300V$ $V_{GE}=-15V$	$T_j = 25  ^{\circ}C$ $T_j = 125  ^{\circ}C$ $T_j = 150  ^{\circ}C$		1.20 2.20 2.50		μC
Reverse recovery energy	E <sub>rec</sub>	$I_F=30A$ $di/dt=2100A/\mu s$ $V_R=300V$ $V_{GE}=-15V$	$T_j = 25 \text{ °C}$ $T_j = 125 \text{ °C}$ $T_j = 150 \text{ °C}$		0.32 0.55 0.65		mJ

<sup>&</sup>lt;sup>2)</sup> values also influenced by parasitic L- and C- in measurement and package.



## **CHIP DRAWING:**





# This chip data sheet refers to the device data sheet Description: AQL 0,65 for visual inspection according to failure catalog Electrostatic Discharge Sensitive Device according to MIL-STD 883 Test-Normen Villach/Prüffeld

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